

<b>Notice of References Cited</b>	Application/Control No. 10/804,103	Applicant(s)/Patent Under Reexamination OTSUKA ET AL.	
	Examiner Arlen Soderquist	Art Unit 1797	Page 1 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	8-105879	04-1996	JP	Sugimori et al.	
	O	11-264815	09-1999	JP	Nakajima et al.	
	P	11-264816	09-1999	JP	Nakajima et al.	
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Zolotov, Y. A. et al, Analytica Chimica Acta 1995, 308, 378-385.
	V	Morosanova, E. et al, Fresenius' Journal of Analytical Chemistry 1998, 361, 305-308.
	W	Ershova, N. I. et al, Analytica Chimica Acta 1998, 364, 235-241.
	X	Malcik, N. et al, Sensors and Actuators B 1998, 53, 211-221.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/804,103		Applicant(s)/Patent Under Reexamination OTSUKA ET AL.	
	Examiner Arlen Soderquist		Art Unit 1797	Page 2 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Morosanova, E. I. et al, Journal of Analytical Chemistry 2000, 55, 486-491.
	V	Sanchez-Pedreno, C. et al Fresenius' Journal of Analytical Chemistry 2000, 366, 811-815.
	W	Sanchez-Pedreno, C. et al, Analytica Chimica Acta 2000, 414, 195-203.
	X	Sanchez-Pedreno, C. et al, Fresenius' Journal of Analytical Chemistry 2001, 369, 680-683.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/804,103	Applicant(s)/Patent Under Reexamination OTSUKA ET AL.	
	Examiner Arlen Soderquist	Art Unit 1797	Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sanchez-Pedreno, C. et al, Talanta 2002, 56, 481-489.
	V	Albero, M. I. et al, Journal of Pharmaceutical and Biomedical Analysis 2002, 29, 779-786.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.